

Search Notes

Application/Control No.

09/784,722

Examiner

Djenane M. Bayard

Applicant(s)/Patent under
Reexamination

TANG ET AL.

Art Unit

2141

SEARCHED

Class	Subclass	Date	Examiner
370	389	6/15/2005	db

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/15/2005	DB